



FAST CMOS OCTAL TRANSPARENT LATCH

IDT74FCT2373T/AT/CT

FEATURES:

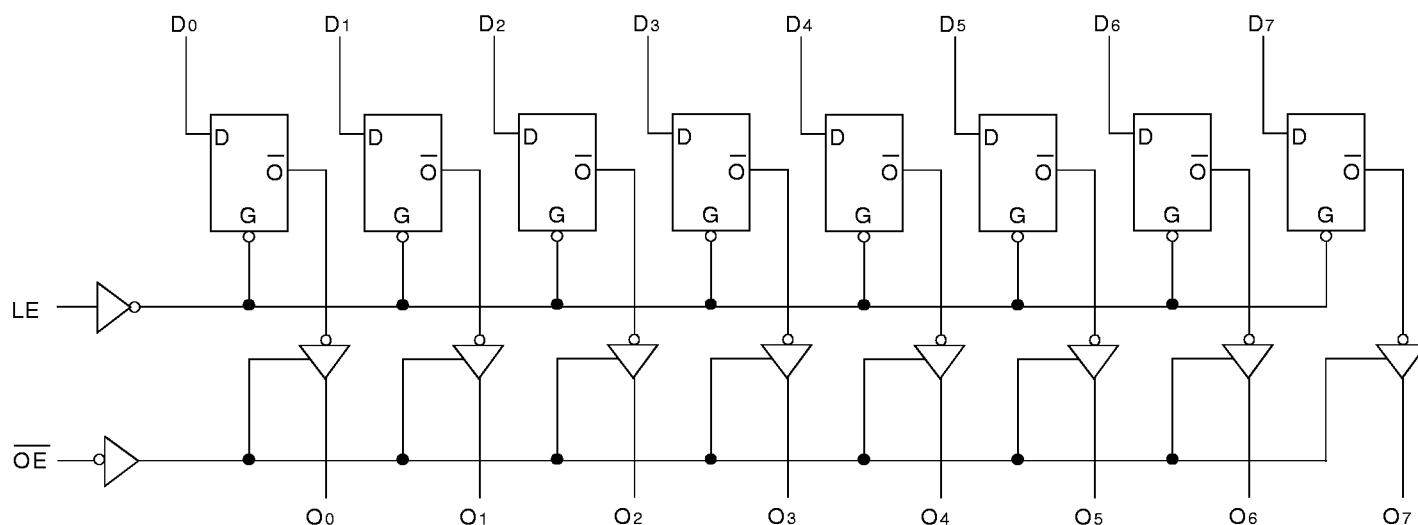
- Low input and output leakage $\leq 1\mu\text{A}$ (max.)
- Extended commercial range of -40°C to $+85^{\circ}\text{C}$
- CMOS power levels
- True TTL input and output compatibility
 - $V_{OH} = 3.3\text{V}$ (typ.)
 - $V_{OL} = 0.3\text{V}$ (typ.)
- Meets or exceeds JEDEC standard 18 specifications
- Product available in Radiation Tolerant and Radiation Enhanced versions
- Available in PDIP, SOIC, SSOP, QSOP, and TSSOP packages
- Std., A and C speed grades
- Resistor output (-15mA I_{OH} , 12mA I_{OL})
- Reduced system switching noise

DESCRIPTION:

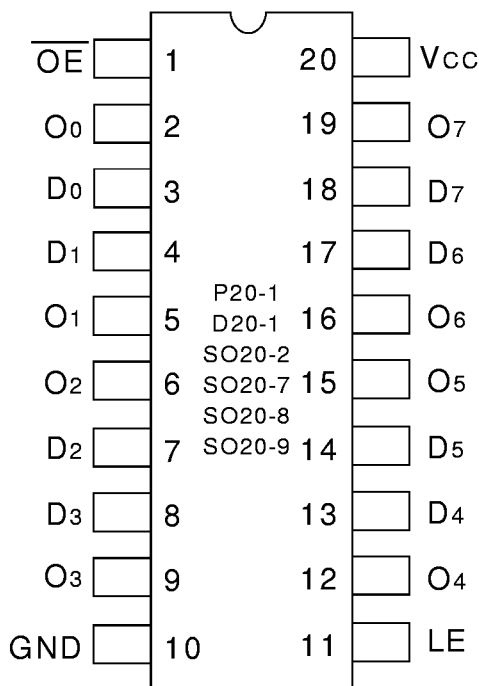
The FCT2373T is an octal transparent latch built using an advanced dual metal CMOS technology. These octal latches have 3-state outputs and are intended for bus oriented applications. The flip-flops appear transparent to the data when Latch Enable (LE) is high. When LE is low, the data that meets the set-up time is latched. Data appears on the bus when the Output Enable ($\overline{OE}$) is low. When $\overline{OE}$ is high, the bus output is in the high-impedance state.

The FCT2373T has balanced drive outputs with current limiting resistors. This offers low ground bounce, minimal undershoot and controlled output fall times-reducing the need for external series terminating resistors. The FCT2373T parts are plug-in replacements for FCT373T parts.

FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATION



PDIP/ SOIC/ SSOP/ QSOP/ TSSOP
TOP VIEW

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Rating	Max.	Unit
V _{TERM} ⁽²⁾	Terminal Voltage with Respect to GND	−0.5 to +7	V
V _{TERM} ⁽³⁾	Terminal Voltage with Respect to GND	−0.5 to V _{CC} +0.5	V
T _{STG}	Storage Temperature	−65 to +150	°C
I _{OUT}	DC Output Current	−65 to +120	mA

8T-link

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed V_{CC} by +0.5V unless otherwise noted.
- Inputs and V_{CC} terminals only.
- Outputs and I/O terminals only.

CAPACITANCE (T_A = +25°C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	6	10	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V	8	12	pF

8T-link

NOTE:

- This parameter is measured at characterization but not tested.

PIN DESCRIPTION

Pin Names	Description
DN	Data Inputs
LE	Latch Enable Input (Active HIGH)
$\overline{OE}$	Output Enable Input (Active LOW)
ON	3-State Outputs

FUNCTION TABLE ⁽¹⁾

Inputs			Outputs
DN	LE	$\overline{OE}$	ON
H	H	L	L
L	H	L	H
X	X	H	Z

NOTE:

- H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
Z = High-Impedance

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Commercial: $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$, $V_{CC} = 5.0\text{V} \pm 5\%$

Symbol	Parameter	Test Conditions ⁽¹⁾	Min.	Typ. ⁽²⁾	Max.	Unit
V_{IH}	Input HIGH Level	Guaranteed Logic HIGH Level	2.0	—	—	V
V_{IL}	Input LOW Level	Guaranteed Logic LOW Level	—	—	0.8	V
I_{IH}	Input HIGH Current ⁽⁴⁾	$V_{CC} = \text{Max.}$	—	—	± 1	μA
I_{IL}	Input LOW Current ⁽⁴⁾					
I_{OZH}	High Impedance Output Current (3-State output pins) ⁽⁴⁾	$V_{CC} = \text{Max.}$	—	—	± 1	μA
I_{OZL}						
I_I	Input HIGH Current	$V_{CC} = \text{Max.}, V_I = V_{CC} (\text{Max.})$	—	—	± 1	μA
V_{IK}	Clamp Diode Voltage	$V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$	—	-0.7	-1.2	V
V_H	Input Hysteresis	—	—	200	—	mV
I_{CC}	Quiescent Power Supply Current	$V_{CC} = \text{Max.}, V_{IN} = \text{GND or } V_{CC}$	—	0.01	1	μA

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾	Min.	Typ. ⁽²⁾	Max.	Unit
I_{ODL}	Input LOW Current	$V_{CC} = 0\text{V}, V_{IN} = V_{IH} \text{ or } V_{IL}, V_{OUT} = 1.5\text{V}^{(3)}$	16	48	—	μA
I_{ODH}	Input HIGH Current	$V_{CC} = 0\text{V}, V_{IN} = V_{IH} \text{ or } V_{IL}, V_{OUT} = 1.5\text{V}^{(3)}$	-16	-48	—	μA
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	2.4	3.3	—	V
V_{OL}	Output LOW Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	—	0.3	0.5	V

NOTES:

- For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0\text{V}$, $+25^{\circ}\text{C}$ ambient and maximum loading.
- Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.
- The test limit for this parameter is $\pm 5\mu\text{A}$ at $T_A = -55^{\circ}\text{C}$.
- This parameter is guaranteed but not tested.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$		—	0.5	2	mA
I_{CCD}	Dynamic Power Supply Current ⁽⁴⁾	$V_{CC} = \text{Max.}$ Outputs Open $\overline{OE} = \text{GND}$ One Input Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.06	0.12	mA/ MHz
I_C	Total Power Supply Current ⁽⁶⁾	$V_{CC} = \text{Max.}$ Outputs Open $f_i = 10\text{MHz}$ 50% Duty Cycle $\overline{OE} = \text{GND}$ $LE = V_{CC}$ One Bit Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.6	2.2	mA
			$V_{IN} = 3.4$ $V_{IN} = \text{GND}$	—	0.9	3.2	
		$V_{CC} = \text{Max.}$ Outputs Open $f_i = 2.5\text{MHz}$ 50% Duty Cycle $\overline{OE} = \text{GND}$ $LE = V_{CC}$ Eight Bits Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$		1.2	3.4 ⁽⁵⁾	
			$V_{IN} = 3.4$ $V_{IN} = \text{GND}$	—	3.2	11.4 ⁽⁵⁾	

NOTES:

- For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0V$, $+25^\circ\text{C}$ ambient.
- Per TTL driven input ($V_{IN} = 3.4V$); all other inputs at V_{CC} or GND .
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
 $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP}/2 + f_i N_i)$
 $I_{CC} = \text{Quiescent Current}$
 $\Delta I_{CC} = \text{Power Supply Current for a TTL High Input } (V_{IN} = 3.4V)$
 $D_H = \text{Duty Cycle for TTL Inputs High}$
 $N_T = \text{Number of TTL Inputs at } D_H$
 $I_{CCD} = \text{Dynamic Current Caused by an Input Transition Pair (HLH or LHL)}$
 $f_{CP} = \text{Clock Frequency for Register Devices (Zero for Non-Register Devices)}$
 $f_i = \text{Input Frequency}$
 $N_i = \text{Number of Inputs at } f_i$
 All currents are in milliamps and all frequencies are in megahertz.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE (1)

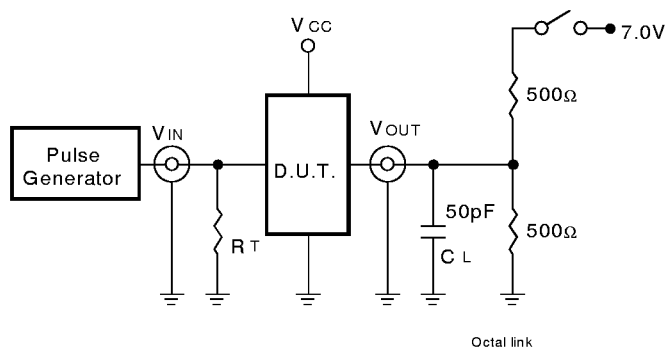
Symbol	Parameter	Condition ⁽¹⁾	FCT2573T		FCT2573AT		FCT2573CT		Unit
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	
t _{PLH} t _{PHL}	Propagation Delay DN to ON	CL = 50pF RL = 500Ω	1.5	8	1.5	5.2	1.5	4.2	ns
t _{PLH} t _{PHL}	Propagation Delay LE to ON		2	13	2	8.5	2	5.5	ns
t _{PZH} t _{PZL}	Output Enable Time		1.5	12	1.5	6.5	1.5	5.5	ns
t _{PHZ} t _{PLZ}	Output Disable Time		1.5	7.5	1.5	5.5	1.5	5	ns
t _{SU}	Set-up Time HIGH or LOW, DN to LE		2	—	2	—	2	—	ns
t _H	Hold Time HIGH or LOW, DN to LE		1.5	—	1.5	—	1.5	—	ns
t _W	LE Pulse Width HIGH ⁽³⁾		6	—	5	—	5	—	ns

NOTES:

1. See test circuit and wave forms.
2. Minimum limits are guaranteed but not tested on Propagation Delays.
3. This parameter is guaranteed but not tested.

TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



SWITCH POSITION

Test	Switch
Open Drain Disable Low Enable Low	Closed
All Other Tests	Open

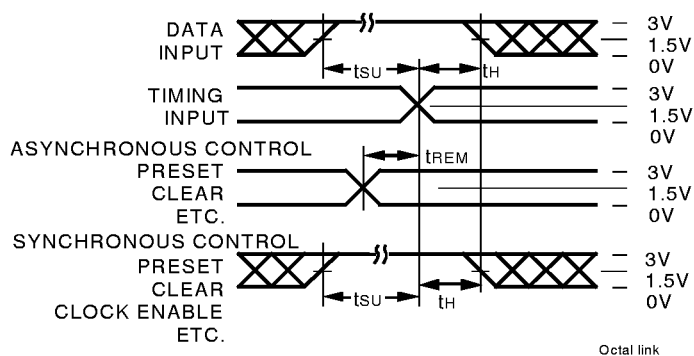
8-link

DEFINITIONS:

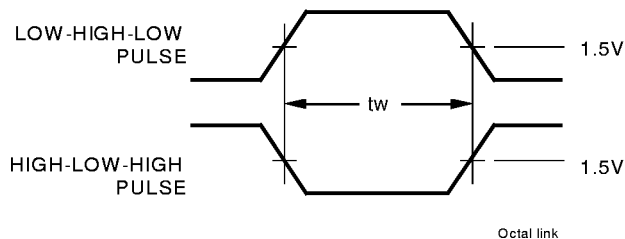
C_L = Load capacitance: includes jig and probe capacitance.

R_T = Termination resistance: should be equal to Z_{OUT} of the Pulse Generator.

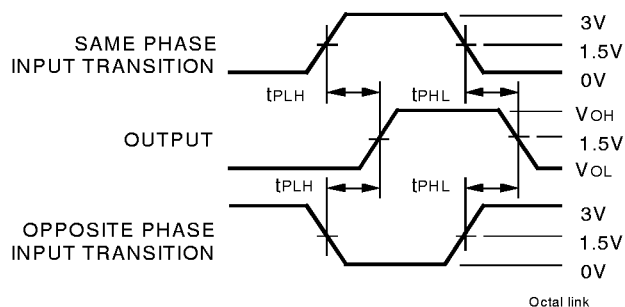
SET-UP, HOLD, AND RELEASE TIMES



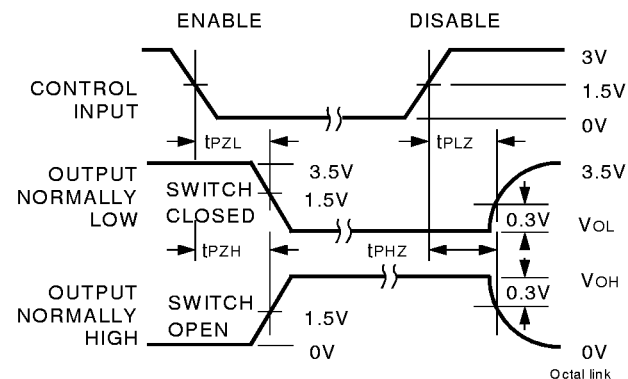
PULSE WIDTH



PROPAGATION DELAY



ENABLE AND DISABLE TIMES



NOTES:

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
- Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_F \leq 2.5\text{ns}$; $t_R \leq 2.5\text{ns}$

ORDERING INFORMATION

IDT	XX	FCT	X	XXXX	X	X		
Temp. Range	Family	Device Type	Package	Process				
						Blank	Commercial	
						P	Plastic DIP (P20-1)	
						D	CERDIP (D20-1)	
						SO	Small Outline IC (SO20-2)	
						PY	Shrink Small Outline Package (SO20-7)	
						Q	Quarter-size Small Outline Package (SO20-8)	
						PG	Thin Shrink Small Outline Package (SO20-9)	
						373T	Octal Transparent Latch	
						373AT		
						373CT		
						2	Balanced Drive	
						74	-40°C to +85°C	



CORPORATE HEADQUARTERS

2975 Stender Way
 Santa Clara, CA 95054

for SALES:

800-345-7015 or 408-727-6116
 fax: 408-492-8674
www.idt.com*

*To search for sales office near you, please click the sales button found on our home page or dial the 800# above and press 2.
 The IDT logo is a registered trademark of Integrated Device Technology, Inc.